

IPW

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of

O'CONNELL, Daniel G.

Serial No. 10/693,953

Art Unit: 2878

Filed: October 28, 2003

Examiner:

For: CELL TRAY

INFORMATION DISCLOSURE STATEMENT

To the Director of the Patent and Trademark Office

Sir:

Under the provisions of 37 C.F.R. 1.56, 1.97 and 1.98, applicant submits herewith copies of publications that the Patent Office may wish to consider in examination of the subject application. The publications are listed on the attached Form PTO 1449 (modified).

Respectfully,

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April 21, 2005

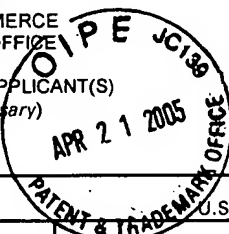
FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)

Date Submitted to PTO: April 15, 2005

ATTY DOCKET NO.
OCEANITSERIAL NO.
10/693,953APPLICANT
O'CONNELL, Daniel G.FILING DATE
October 28, 2003

GROUP



U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	6,208,886	3/27/2001	Alfano et al.			
	AB	6,818,907	11/16/2004	Stark			
	AC	2003/0215844	11/20/2003	Chapsky et al.			
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO	
	AL							
	AM							

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

	AN	Milster et al.; <u>Super-Resolution by Combination of a Solid Immersion Lens and Aperture</u> ; The Japanese Society of Applied Physics, Part 1, No.3B: March 2001
	AO	Hecht et al.; <u>scanning near-field optical microscopy with aperture probes: Fundamentals and applications</u> ; Special Topic: Near-field Microscopy and Spectroscopy; Journal of Chemical Physics; Vol. 112, No.18; May 8, 2000
	AP	Betzig & Chichester; <u>Single Molecules Observed by Near-field Scanning Optical Microscopy</u> ; Science, New Series; Vol. 262, No.5138; November 26, 1993; Pages 1422-1425
	AQ	Mansfield & Kino; <u>Solid Immersion Microscope</u> ; Appl. Physics Letter; Vol.57, No. 24; December 10, 1990

EXAMINER

DATE CONSIDERED

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
	AC						
	AD						

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

	AE	D. V. Palanker et al.; <u>On contrast parameters and topographic artifacts in near-field infrared microscopy</u> ; Journal of Applied Physics, Vol. 88, No. 11; December 1, 2000
	AF	Tom D. Milster et al.; <u>The Nature of the Coupling field in Optical Data Storage using Solid Immersion Lenses</u> ; The Japanese Society of Applied Physics, Part 1, No. 3B: March 1999
	AG	Jonathan D. Bui et al.; <u>Probing intracellular dynamics in living cells with near-field optics</u> ; Journal of Neuroscience Methods 89 (1999) 9-15; February 27, 1999
	AH	
	AI	
	AJ	
	AK	
	AL	
	AM	

EXAMINER

DATE CONSIDERED